2026 AGENDA

Correct as of 16-Apr-2025 5:44am
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Day 1 - Monday 7th April 2025

18:00 **Pre-conference networking drinks reception**

Day 2 - Tuesday 8th April 2025

08:00	Registration and welcome refreshments
08:50	Housekeeping by Chris Meadows and Tim Bettles - Conference Chairs

Expanding the emission envelope

09:00	**Expanding the Spectral Range of GaN-based SLEDs** *Presented by Marco Malinverni - Exalos*
09:15	**Perfecting GaN VCSEL Production Process** *Presented by Tetsuya Takeuchi - Meijo University*
09:30	**Connected Metrology for Growth and Characterization of InP and GaAs Laser Structures – from Epi to Etch** *Presented by Iris Claussen - LayTec AG*
09:45	**Germanium as an Enabler for Large Volume Production in PV and Photonics** *Presented by Ivan Zyulkov - Umicore*
10:00	**InP NIR VCSELs from 1.3 μm to beyond 2 μm for Single Mode and Multi Mode Applications** *Presented by Christian Neumeyr - Vertilas*
10:15	**Ultraviolet to Infrared in a Single Spectrum** *Presented by Yves Lacroix - YSystems Ltd*
10:30	**The Power of Pseudomorphic Nitrides** *Presented by Leo Schowalter - Lit Thinking*
10:45	Morning Break

GaN: Going beyond fast charging

11:25	**Achieving Avalanche in GaN-on-silicon Diodes** *Presented by Farid Medjdoub - University of Lille*
11:40	**Characterizing GaN: Challenges and Advances in Next-Generation Semiconductor Metrology** *Presented by Áron Pekker - Semilab*
11:55	**X-ray Metrology Solutions for Compound Semiconductors from Labs to Fabs.** *Presented by Assunta Vigliante - Rigaku*
12:10	**AIXTRON Leading Epitaxy Solutions for High Volume Manufacturing of GaN-based Power Devices** *Presented by Dr. Nicolas Muesgens - Aixtron*
12:25	**Improving GaN Defect Analysis and Characterization with Novel Electron Microscopy Workflow** *Presented by Antonio Mani - Thermo Fisher Scientific*
12:40	**GaN's Takeover: The Next Big Leap in Power Electronics** *Presented by Ezgi Dogmus - Yole Group*
12:55	Lunch Break
14:25	**Harnessing the Underestimated Potential of GaN in the Digitalization Revolution: A Catalyst for Unforeseen Innovation in Energy Efficiency** *Presented by Roberto Crisafulli - STMicroelectronics*
14:40	**Epitaxial GaN Growth using MBE for the Development of Next-Generation Devices** *Presented by Romain Bruder - Riber*
14:55	**VECTOR: Advancing SEM Metrology with Automation and Versatility** *Presented by Amanda Wscieklica - Raith*
15:10	**Driving Adoption of GaN for Power Electronics via 300mm Technology** *Presented by Rudy Parekh - Veeco*
15:25	**Advancement in X-Ray Metrology for High Volume Manufacturing of GaN Based Power Devices** *Presented by Qian Zheng - Bruker*
15:40	Afternoon Break

Maintaining momentum for the microLED

16:20	**Perfecting the Polychromatic Pixel** *Presented by Michelle Chen - Q-Pixel Inc*
16:35	**MicroSolid Printing: Redefining the Future of MicroLED Displays** *Presented by Reza Chaji - VueReal*
16:50	**Leveraging NIL for μLED Lens Packaging** *Presented by Thomas Achleitner - EV Group*
17:05	**The Future of MicroLED Displays: Which Applications Are Leading in 2025?** *Presented by Raphaël Mermet-Lyaudoz - Yole Group*
17:20	**Pioneering Mass Production and Commercialisation of MicroLED Microdisplays for AR** *Presented by Kunal Kashyap - Porotech*

17:35 **Revolutionising microLED Displays with Nanowires**
Presented by Pierre Tchoulfian - Aledia

17:50 **Closing Remarks**

18:00 **Networking Drinks / Dinner Reception**

Day 3 - Wednesday 9th April 2025

08:00	**Registration and welcome refreshments**
08:50	**Housekeeping by Chris Meadows and Tim Bettles - Conference Chairs**

Optimising opportunities for SiC success

09:00	**20 Years of SiC Innovation Leadership: Trench-Assisted Planar Gate Technology** *Presented by Llewellyn Vaughan-Edmunds - Navitas*
09:15	**Solving Challenges in Compound Semiconductors: An Equipment Supplier's Perspective** *Presented by David Britz - Applied Materials*
09:30	**Building the World's Most Cost-efficient SiC Fab** *Presented by Peter Friedrichs - Infineon*
09:45	**Integrated Metal Etch and Photoresist Strip Solution for SiC Manufacturing** *Presented by Bernhard Hammerl - Siconnex Customized Solutions GmbH*
10:00	**High Sensitivity & Throughput Defect Inspection Technologies for SiC and GaN Power Technologies** *Presented by Mike Rosa - Onto Innovation*
10:15	**SCREEN's Sustainable Cost-of-Ownership (CoO) Portfolio for Wafer Inspection and Thickness Measurement Tools and HVM experience** *Presented by Alessandro Rossi - SCREEN SPE*
10:30	Morning Break
11:10	**Artificial Intelligence for SiC Yield Optimization** *Presented by Marius Fischer - Nanotronics*
11:25	**PVA TePla Metrology Solutions for Compound Semiconductors** *Presented by Ivan Orlov - PVA TePla AG, and Markus Stöhr - PVA TePla AG*
11:40	**How Artificial Intelligence Heralds the New Era of Wafering** *Presented by Malte Mueller - Lapmaster Wolters*
11:55	**Crystal Orientation for Optimizing Quality and Yield throughout the Process Chain** *Presented by Andrey Zameshin - Malvern Panalytical*
12:10	**How to save process cost in your SiC/GaN production using best in class power supplies?** *Presented by Yannick Schneider - TRUMPF*
12:25	Lunch Break

Ultra-wide bandgap materials: The ultimate devices

Sponsored by Precision Fabricators

13:55	**Prospects of (ultra) Wide Bandgap Oxide ICs** *Presented by Xiaohang Li - KAUST*
14:10	**A Solution to Doping AlN Enabling a New Era of Nitride Semiconductors** *Presented by Alan Doolittle - Georgia Institute of Technology*
14:25	**Electric Field Engineering to Unlock the Potential of Gallium Oxide Power Devices** *Presented by Nolan Hendricks - AFRL (Air Force Research Laboratory)*
14:40	**Efficient Diameter Enlargement of Bulk AlN** *Presented by Carsten Hartmann - Leibniz-Institut für Kristallzüchtung (IKZ)*
14:55	**The promise of cubic Boron Nitride (c-BN)** *Presented by Siddha Pimputkar - Lehigh University*
15:10	**Closing Remarks**

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